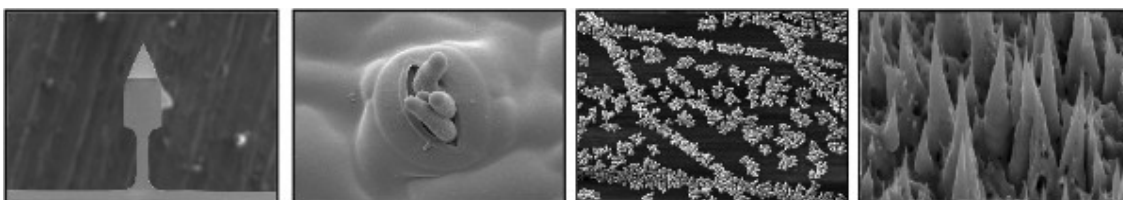


---

# NANO IMAGING LAB

**Newsletter**

VOLUME IV, October 7th, 2019



---

## Target Preparation & Ion Beam Milling

On 17 September 2019 the Nano Imaging Lab hosted a very valuable hands-on workshop on sample preparation for SEM, TEM and LM techniques. Seven participants got together in the NI Lab to learn more about optimizing their samples to obtain better results by using the two preparation tools LEICA EM TXP and LEICA EM TIC 3X, both available in the NI Lab.

Wolfgang Grünewald and Till Samtleben from Leica Microsystems illustrated the broad spectrum of applications of the two machines and also accepted samples from the participants for demonstration and practice. They were happy to give everybody good advice for their individual samples or problems and at the end of the day everyone went home with lots of useful insights.



### LEICA EM TXP

Once the sample is clamped into the specimen holder and inserted into the pivot arm, the specimen can be

- **cut**
- **milled**
- **sawn**
- **ground**
- **polished**

consecutively without removing the sample but simply changing the tools while observing the process directly through the stereomicroscope.



### LEICA EM TIC 3X

For further surface preparation of a hard, soft, porous, heat sensitive, brittle or heterogenous material this tool with its **triple ion-beam milling system** can help to optimize the sample for SEM or AFM investigation, where high quality cross-sections and a **clean polished surface** is highly desirable. Even **contrast enhancement** of a material can be achieved.

## Workshops at the NI Lab

The Nano Imaging Lab is considering to offer workshops on the technologies available in this lab in order to give customers more detailed information about the extensive range of preparation, imaging and analyzing methods, that we use (Transmission Electron Microscopy, Scanning Electron Microscopy plus EDX-Analysis, Focused Ion Beam, Atomic Force Microscopy and various preparation methods, also look at our [website](#)). Clients would learn which technique is suitable for their project and would get individual consultation and advice.

With an adequate number of interested customers we could give an overall overview of all methods, how they work and what you can achieve with them. In addition we could organize more intense trainings on just one or two selected methods.

Especially for industrial clients, who barely have access to this kind of equipment these

workshops might be interesting.

We would be very grateful to get as much feedback as possible to this idea.

Please write to us if you are interested! Your input, wishes and comments are very welcome.

We await your emails at [nanoimaging@unibas.ch](mailto:nanoimaging@unibas.ch) .

---

*Copyright © 2019 Nano Imaging Lab, All rights reserved.*

<http://nanoimaging.unibas.ch>

[unsubscribe](#) | [view in browser](#)

